DynamiX

A prototype high-framerate, high-dynamic-range hard X-ray detector for 4th generation synchrotrons

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On behalf of the XIDyn Collaboration iWoRiD 2025





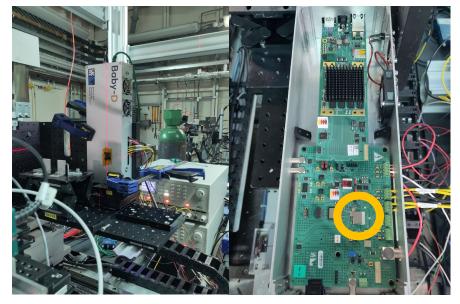




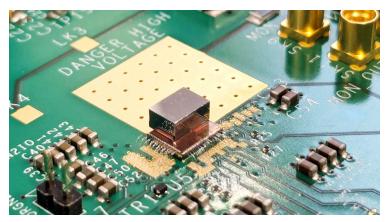


DynamiX Overview

- Charge-integrating hybrid pixellated detector system prototype
- Aims to meet challenges of synchrotron upgrades
 - Higher fluxes → new ASIC architecture
 - Higher energies → CZT sensor material
- 16 x 16 pixels on 110µm pitch
- 534kHz (adjustable) framerate to match Diamond orbit
- Readout at 14Gbps



Aligning DynamiX at Diamond Light Source (DLS)



DynamiX bonded to 2mm Redlen HF-CdZnTe











Content

- Motivations
- Chip architecture
- Results from testing at DLS B16
- Summary







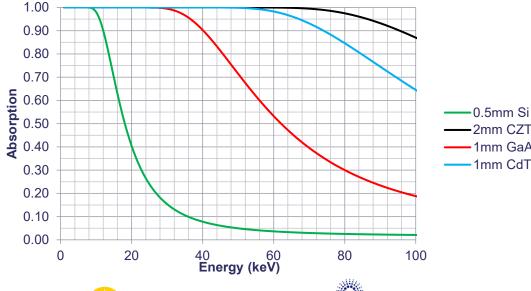




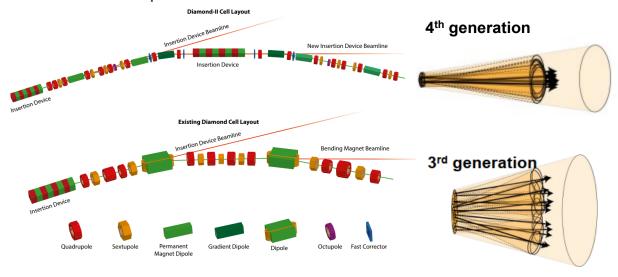


Motivation

- Diamond II upgrade
- Up to 10¹¹⁻¹² ph/mm²/s
- Many beamlines >20keV
- Mpixels for 2029



Credit: https://www.diamond.ac.uk/Diamond-II.html







—0.5mm Si

-1mm GaAs

-1mm CdTe



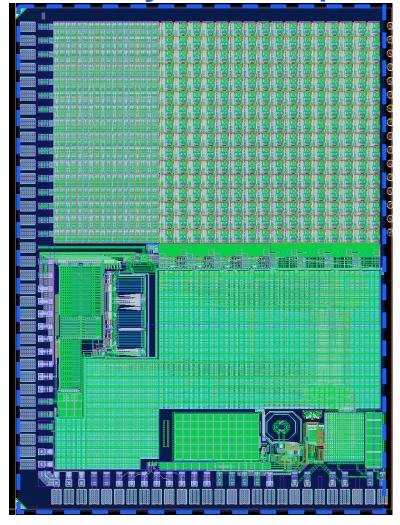




DynamiX Spec

Parameter	DynamiX
Flux	>10 ⁹ ph/s/pixel
Pixel Size	110 µm
Frame Rate	534 kHz (Synchrotron determined)
Dynamic Range	>10 ¹¹ ph/mm ² /s
Energy	25keV typical
Noise Level	<single photon<="" th=""></single>











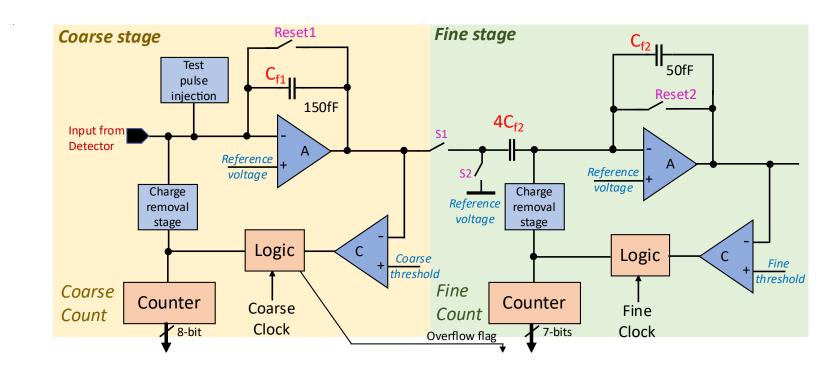




Chip Architecture

Incremental digital integration (per pixel):

- 2 stage charge cancellation circuit
- Signal integrated in coarse stage cancelled and remainder passed to fine stage
- Coarse and Fine counters output





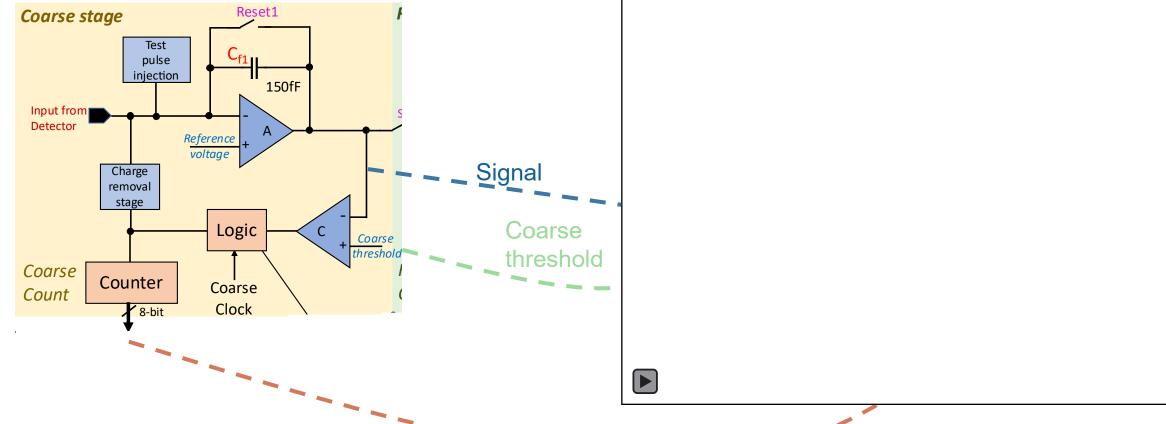








Coarse Stage (<6400 ph/pix/frame @ 30keV)







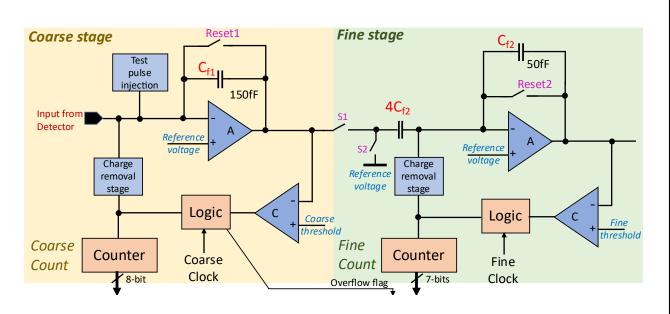


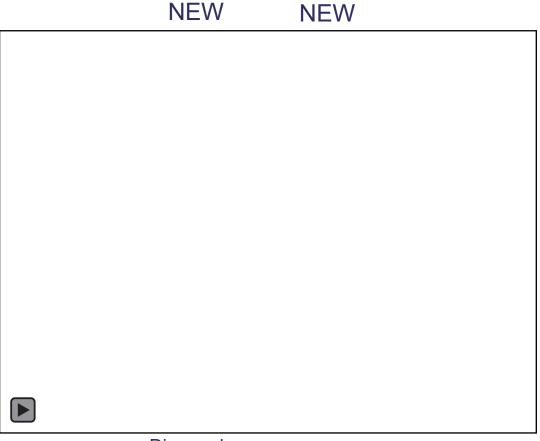






Transfer and Fine Stage (<25 ph/pix/frame @ 30keV)





Diamond











Results from beam tests at DLS B16





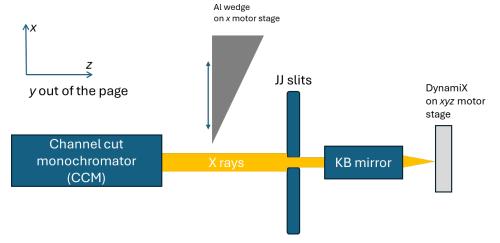




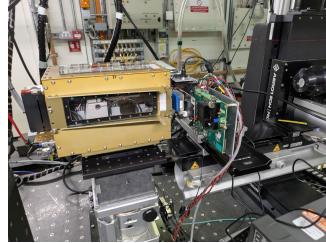


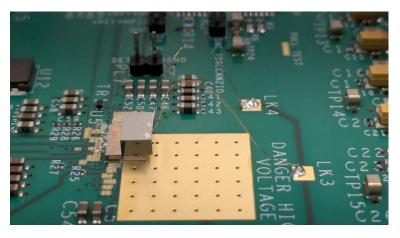
Setup at DLS B16 Test Beamline

- Focusing used to access sub-pixel-sized beam
- Beam energies of 20,30,40 and 50keV
- Sensor biased to -1000V
- Later switched to DCM to access higher fluxes at 20keV













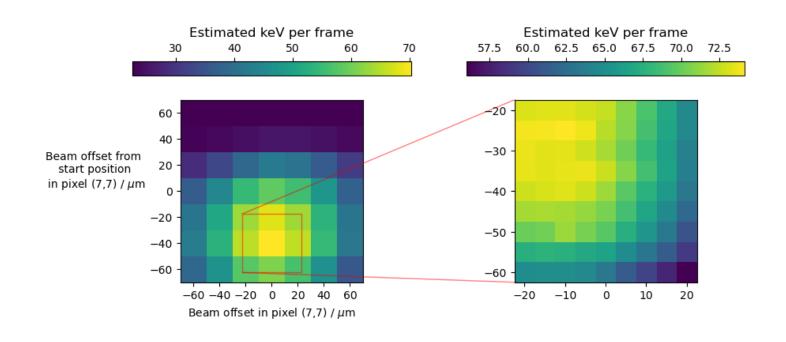






Charge sharing – raster scanning beam within pixel (20keV, ~20µm beam)

- Measured signal in pixel strongly depends on beam alignment to centre of pixel
- Evidence of charge sharing to neighbouring pixels in CZT
- Destroys ability to resolve single photon peaks → challenging to calibrate without pencil beam centred in-pixel













Single photon peaks

 Able to resolve single-photon peaks (up to 10 single-photon peaks for 20keV beam)

■ Width $\sigma \approx 5.7 \text{keV}$ ($\approx 1200 \text{ e}^{-} \text{RMS}$)

Photodiode-measured fluxes:

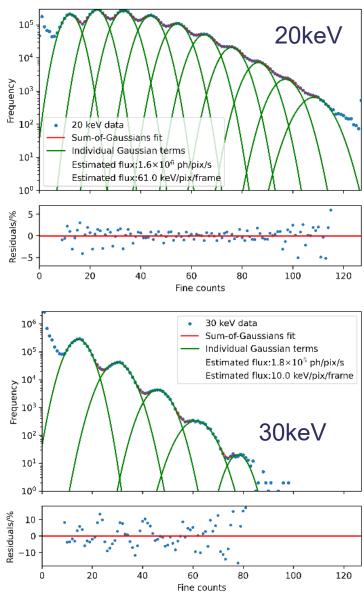
○ 20keV: 1.58 x10⁶ ph/pix/s

○ 30keV: 2.80 x10⁵ ph/pix/s









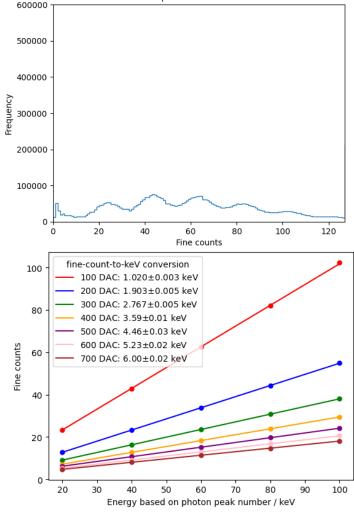




Single photon peaks – changing fine

packet size

- Measurements taken at 20keV, flux ≈1.6x10⁶ ph/s/pix
- Can change digitisation resolution at expense of dynamic range
- Smaller packets → more packets to remove same charge
- Better quality fit with smaller packets → easier to estimate noise
- Settled on packet size 100 DAC as this looks like 1 fine count ≈ 1 keV



Fine packet size = 100 DAC









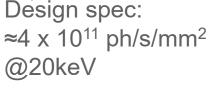


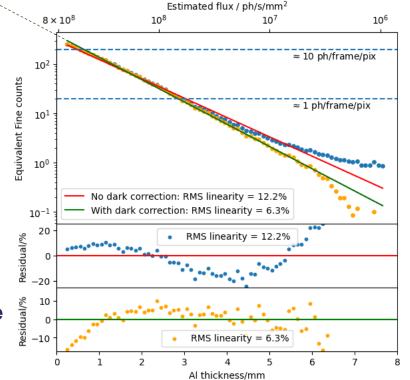
Linearity with increasing flux

xian spec.

Limit of flux from X ray set: ≈3x10¹⁰ ph/s/mm² equiv. @ 20keV

20keV beam, moving Al wedge into beam





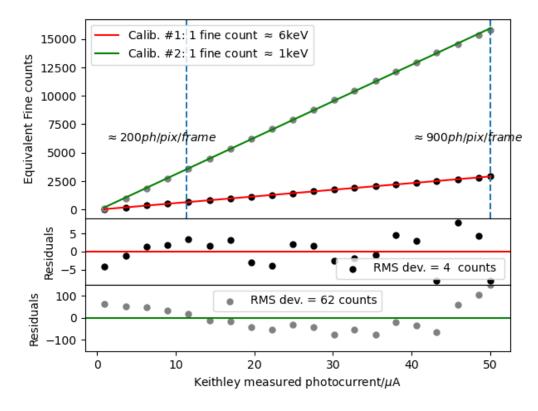
Limited by flux available at the beamline, not the DynamiX detector







160kV W X-ray set (polychromatic)

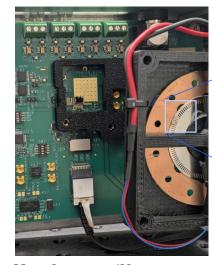


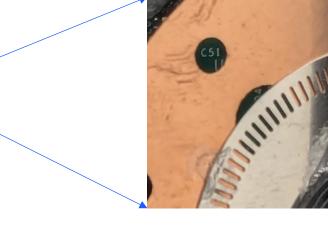


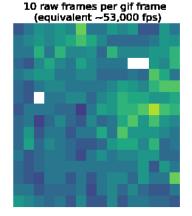


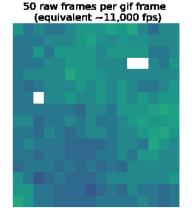
Whole array measurements

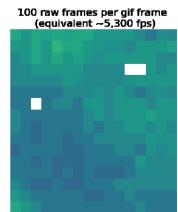
- Imaged a spinning slitted disc (copper and steel) at 533kHz
- 100kV tube voltage, 30mA tube current
- Frames flat-field corrected
- Averaged over windows of 10,50 and 100 frames















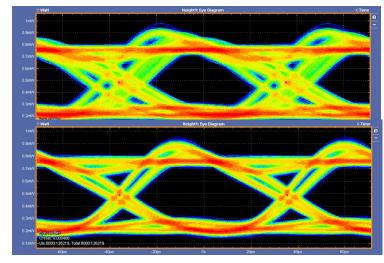






14 Gbps Serialiser Results

- Aurora encoded 66b64b CML
- 14 Gbps working and continuously writing to disc at 534 kfps
- Data passes through retimer IC → allows inspection of eye quality
- Conversion to optical via Samtec FireFly close to ASIC
- Receiver and frame built in FPGA with 100G UDP out



Eye diagrams without and with retiming



Samtec FireFly and retimer IC next to DynamiX ASIC





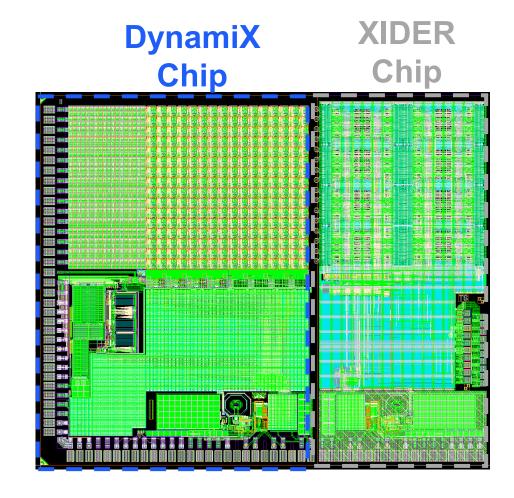






Towards the full-scale ASIC, XIDyn

- 192 x 144 pixel ASIC, combining XIDER and DynamiX designs
- Improvements to pixel design, including:
 - Increased trim range for calibration of thresholds & packet sizes
 - Switch to disconnect front end from pixel during transfer to prevent saturation
- Submission planned for autumn this year, with wafers expected back in spring







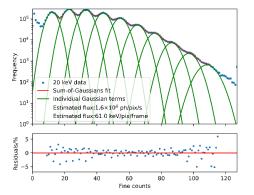




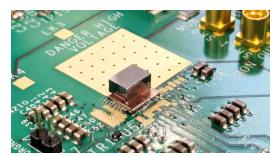


Summary

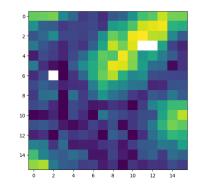
- Continuous full-frame readout at 534 kHz
- Able to resolve single photons with width $\sigma \approx 5.7 \text{keV}$
- Measurements taken in range
 <1ph/pix/frame → ≈900 ph/pix/frame
- Submission of full ASIC in autumn, tileable on 3 sides
- Upcoming beamtimes at Diamond & ESRF to go to higher fluxes



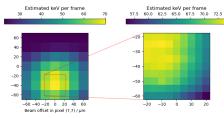
Single-photon peaks @ 20 keV



The DynamiX ASIC with Redlen HF-CZT



Still from imaging spinning slitted disc at 534kfps



Rasting scanning beam within pixel











Additional Slides



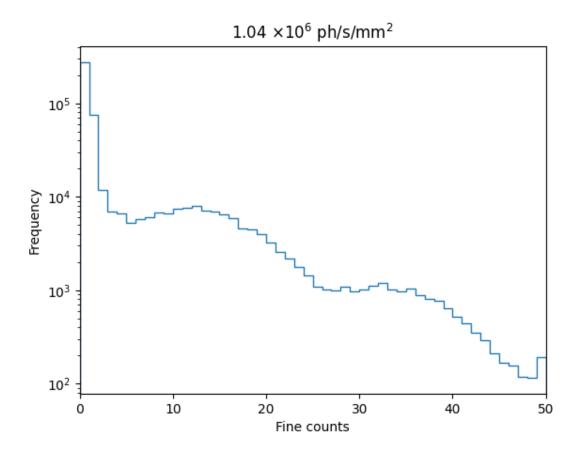




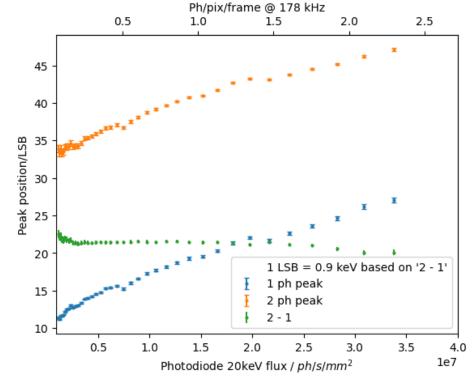




Leakage current shift (FL = 3 Diamond turns)



- 1 and 2 photon peaks move to higher channel numbers with increasing flux
- With FL = 1 turn, beam 50 μ m x 50 μ m, excess leakage current density in this flux range \approx 41 nA/mm²
- This effect has been seen in Redlen HF CZT before, e.g. Cline and XIDER







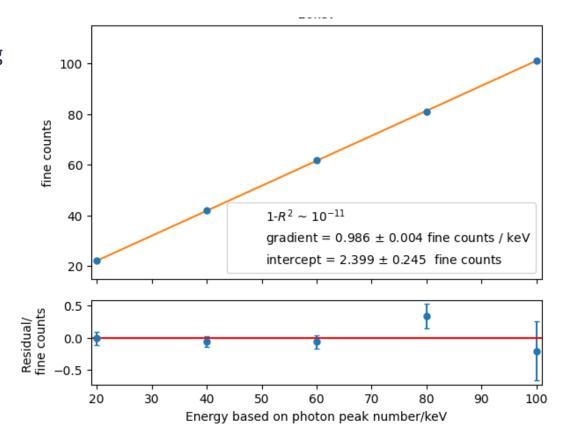






(aim: 1 coarse = 64 fine)

1.Determine ADU → keV conversion from photon peak spacing







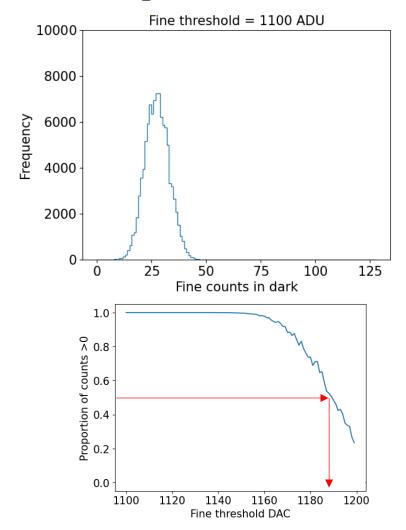






(aim: 1 coarse = 64 fine)

- 1.Determine ADU \rightarrow keV conversion from photon peak spacing
- 2. Change fine threshold to move noise peak to 0
 - Find threshold such that 50% counts are >0











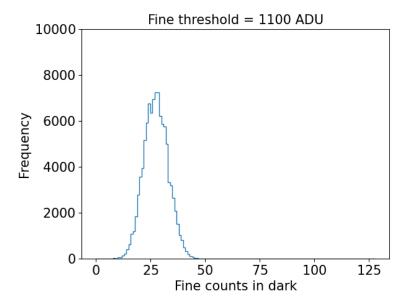


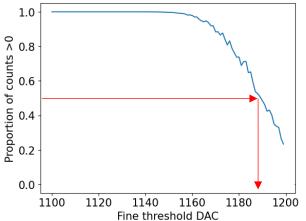
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Can also estimate noise:

- Look at σ of dark counts where distribution is well away from 0
- $\sigma \approx 5.50 \text{ LSB} \approx 5.57 \text{ keV} \approx 1210 \text{ e}^{-1}$
- 150fF fine stage feedback, includes leakage + sensor capacitance















Calibrating from single photon peaks (aim: 1 coarse = 64 fine)

- 1.Determine ADU → keV conversion from photon peak spacing
- 2. Change fine threshold to move noise peak to 0
 - Find threshold such that 50% counts are >0
- 3. Find test pulse setting to give 64 fine counts (≈65 keV)





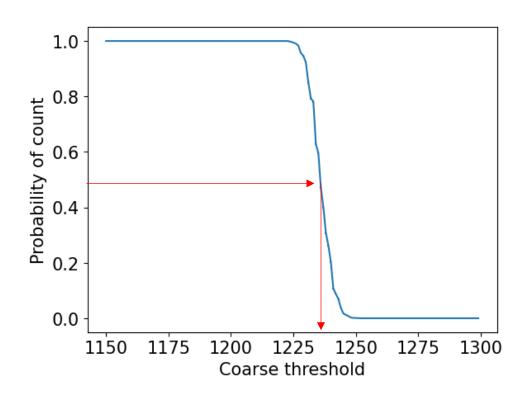






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- 1.Determine ADU → keV conversion from photon peak spacing
- 2. Change fine threshold to move noise peak to 0
 - Find threshold such that 50% counts are >0
- 3. Find test pulse setting to give 64 fine counts (≈65 keV)
- 4. Sweep coarse threshold while injecting 64 fine counts
 - Find threshold such that 50% chance of triggering
 - Set threshold slightly higher to avoid cancelling below baseline







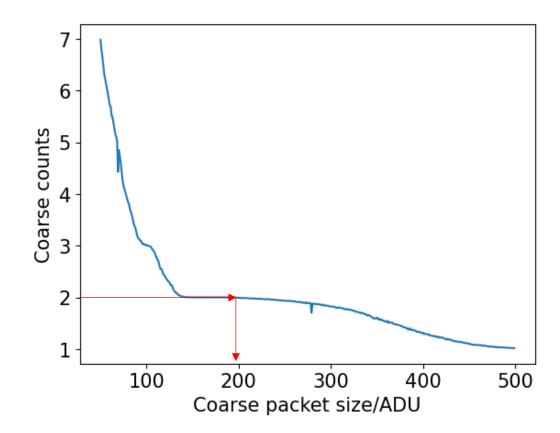






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- 5.Inject 3 coarse counts (=3 x 64 fine counts) and sweep coarse packet size
 - Find maximum packet corresponding to 2 coarse counts













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6. Fine-tune coarse packet size by verifying goodness of fit while injecting increasing charge per frame









'thresh

100

400

300

200

100

50

counts

Equivalent fine

Residual/ fine counts



Coarse packet size = 130

Fit only where injected charge < coarse

200

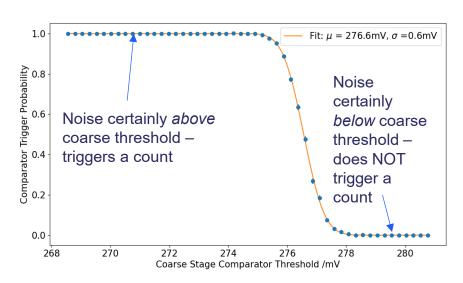
Injected charge/keV



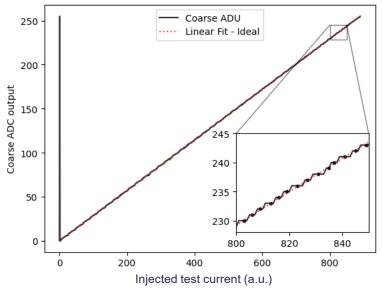
300

400

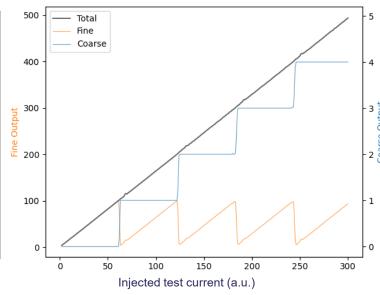
Pixel Test Results – Coarse Stage (inbuilt test pulse)



Sweep coarse stage threshold → measure coarse output → repeat to obtain probability of triggering → determine dark noise



Vary input test current → measure coarse ADC output



Vary input test current → measure coarse and fine counts





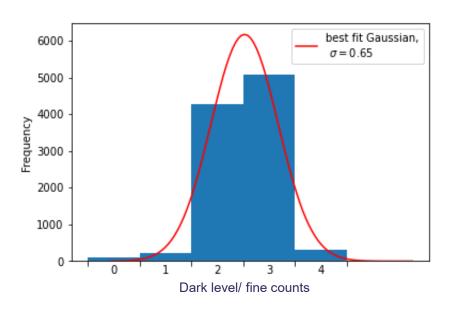






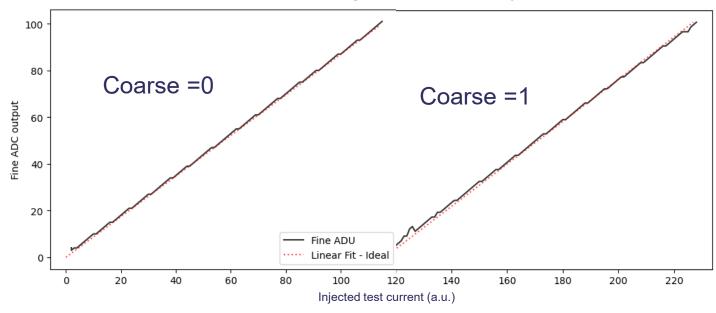
Pixel Test Results – Fine Stage (inbuilt test pulse)

1 fine count = 0.25 of 30keV Photon



No current injected → measure counts due to noise

Fine stage ADC linearity



Increase injected current → measure fine ADC output











Single photon peaks

- Monochromatic beam focused to subpixel level ≈50 μm x 50 μm and centred in pixel
- Can resolve single photon peaks with a width σ ≈ 5.7keV (~1200 e- RMS)
- Misalignment between peaks of same energy:

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\mu_{2x20 \text{ keV}} \neq \mu_{40 \text{ keV}} 

\mu_{3x20 \text{ keV}} \neq \mu_{2x30 \text{ keV}}
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. . .

 Thought to be due to flux-dependent excess leakage current in HF-CZT

